

# What Can be Measured by SANS and Reflectometry?

Charles Glinka

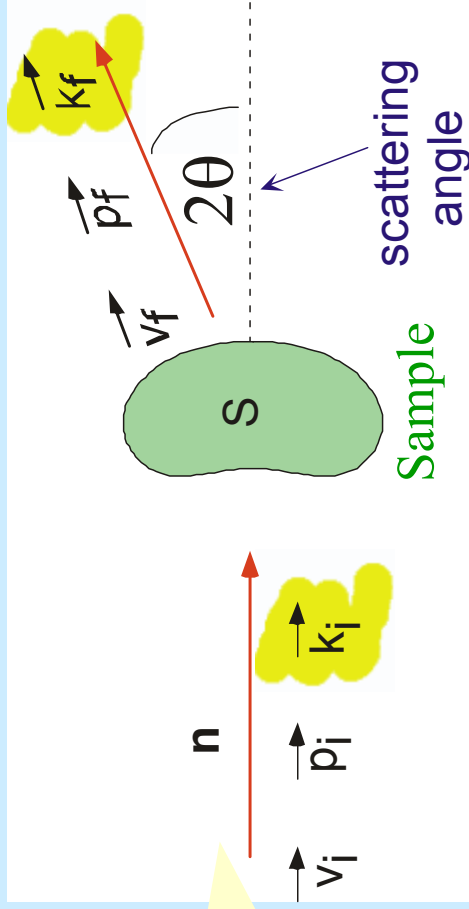
NIST Summer School on SANS and  
Reflectometry from Submicron Structures

June 3-7, 2002

# Concepts Common to SANS and NR

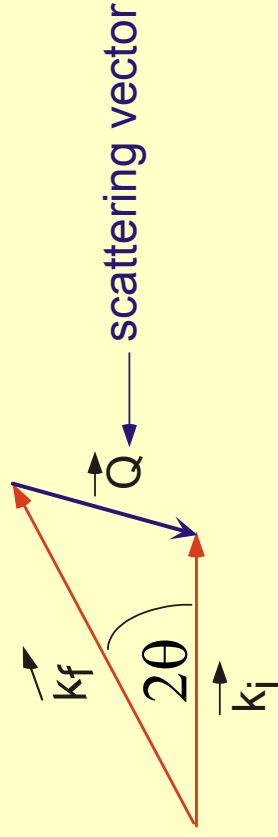
Collimated beam of monochromatic neutrons incident on sample, S

Incident neutron wave vector,  $|\vec{k}_i| = \frac{2\pi}{\lambda_i}$



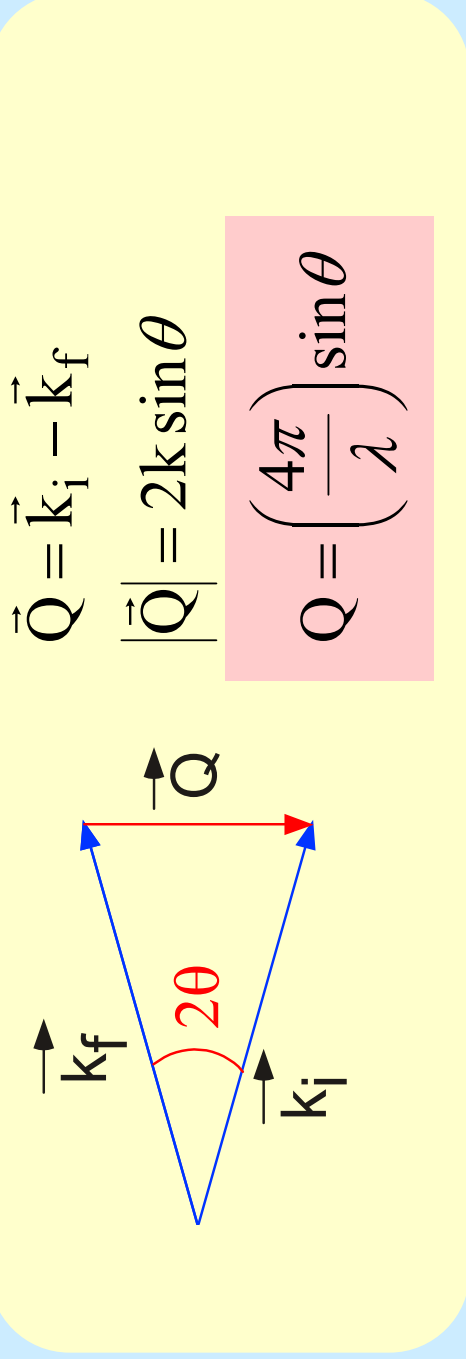
Scattered neutrons counted as a function of scattering angle,  $2\theta$

**Scattering Triangle**



$$\vec{k}_i - \vec{k}_f = \vec{Q}$$

For elastic scattering ( $k_i = k_f = 2\pi/\lambda$ )



Recall Bragg's Law  $\longrightarrow \lambda = 2d \sin \theta$

$$\text{or } d = \frac{\lambda}{2 \sin \theta} = \frac{2\pi}{\left( \frac{4\pi}{\lambda} \right) \sin \theta} = \frac{2\pi}{Q}$$

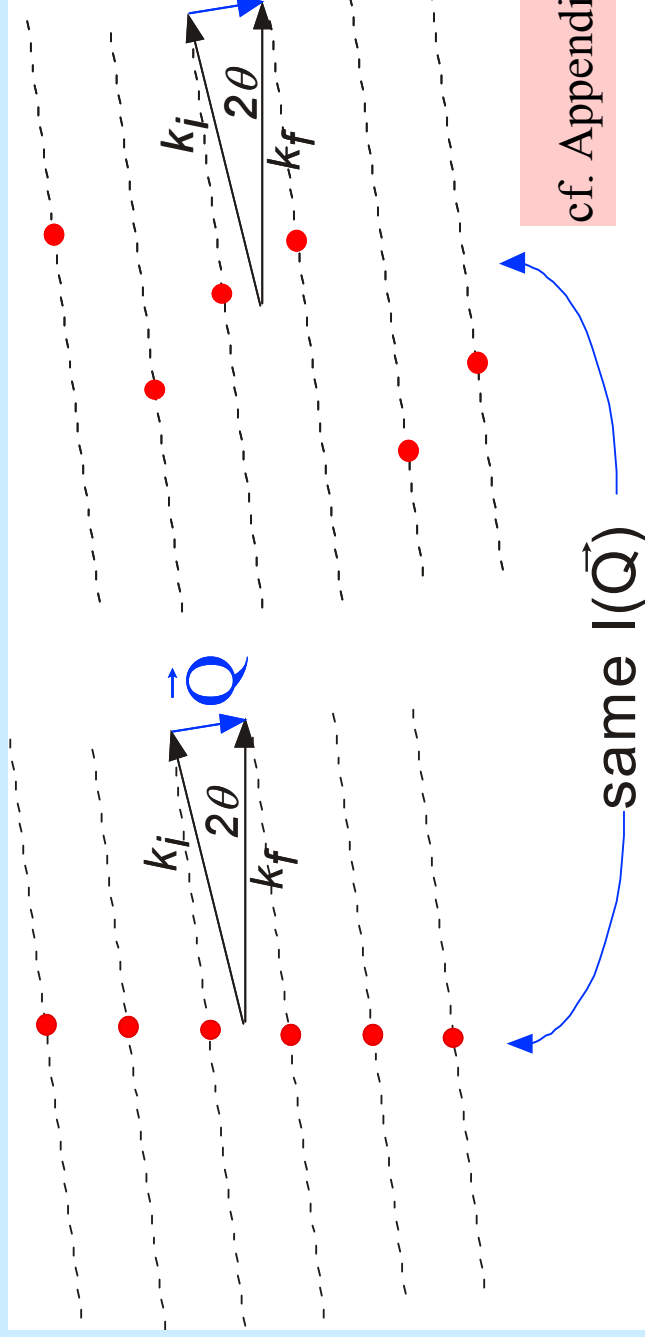
In general, diffraction (SANS or NR) probes length scale

$$d \approx \frac{2\pi}{Q}, \text{ for small scattering angles, } d \approx \frac{\lambda}{2\theta}$$

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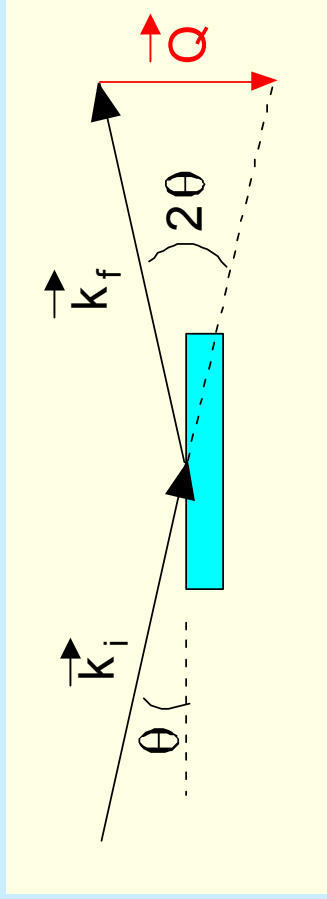
More specifically, diffraction (SANS or NR) probes structure in the direction of  $\vec{Q}$ , on a scale,  $d \approx 2\pi/|\vec{Q}|$



# Diffraction Probes Structure in the Direction of $\vec{Q}$

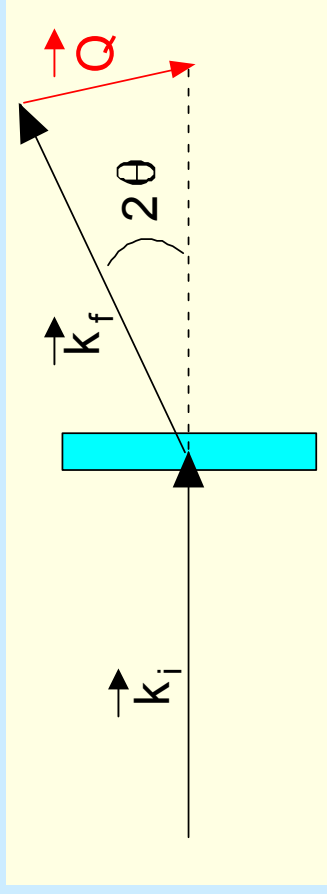
$$\vec{k}_i - \vec{k}_f = \vec{Q}$$

## Specular Reflection Geometry



Reflectivity probes structure perpendicular to surface (parallel to  $\vec{Q}$ ), and *averages over structure in plane of sample.*

## SANS Geometry



SANS probes structure in plane of sample (parallel to  $\vec{Q}$ ), and *averages over structure perpendicular to sample surface.*

# Length Scales Probed by SANS and NR

Small-Angle Neutron Scattering (SANS) probes structure on a scale  $d$ , where

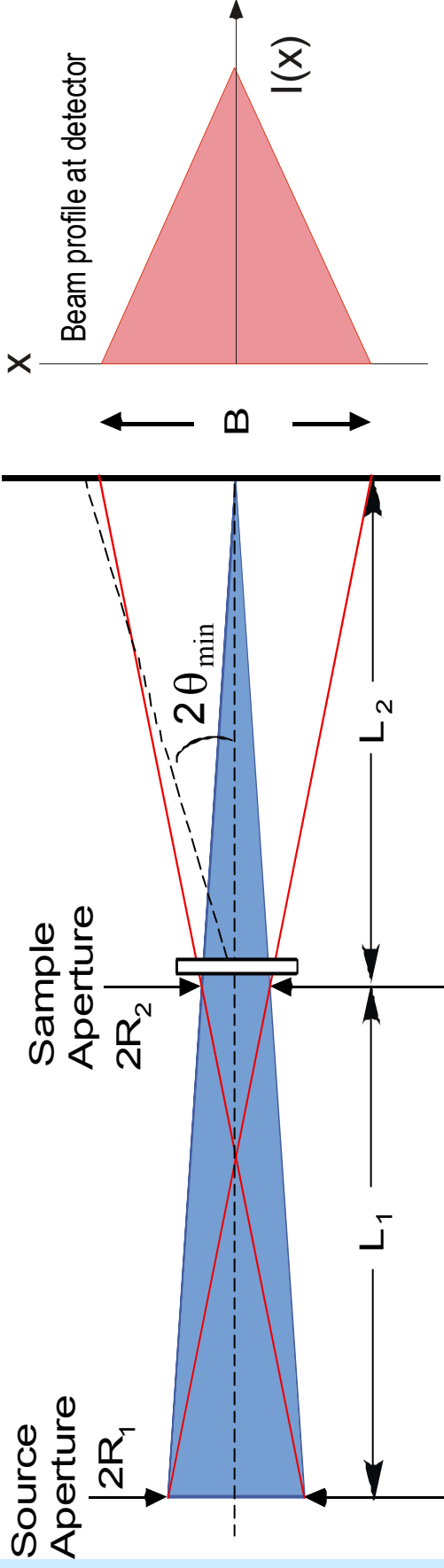
$$d \approx \frac{2\pi}{Q} \approx \frac{\lambda}{2\theta} \quad (\text{scattering angle})$$

$$0.5 \text{ nm} < \lambda < 2 \text{ nm} \quad (\text{cold neutrons})$$

$$0.1^\circ < 2\theta < 10^\circ \quad (\text{small angles})$$

$$1 \text{ nm} < d < 300 \text{ nm}$$

## SANS PINHOLE COLLIMATION GEOMETRY



$$I(2\theta_{\min}) \propto \left( \frac{R_1 R_2}{L_1 L_2} \right)^2 \propto (2\theta_{\min})^4$$

For 'optimal' geometry, where  $L_1 = L_2$ ,  $R_1 = 2R_2$

# Length Scales Probed by SANS and NR

NR probes structure on a scale  $d$ , where

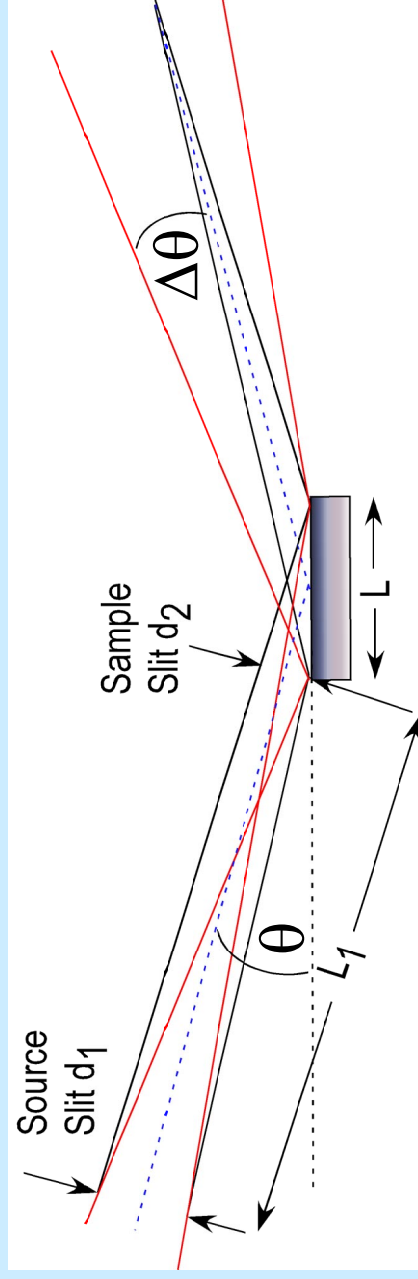
$$d \approx \frac{2\pi}{Q} \approx \frac{\lambda}{2\theta} \quad (\text{wavelength})$$

(reflection angle)

$$0.4 \text{ nm} < \lambda < 0.6 \text{ nm}$$

$$0.06^\circ < \theta < 20^\circ \quad (\text{small angles})$$

$$0.5 \text{ nm} < d < 500 \text{ nm}$$



$$I(\theta) \propto \left( \frac{d_1 d_2}{L_1 L_2} \right) = \left( \frac{2L^2 \sin^2 \theta}{L_1 L_2} \right), \quad \Delta\theta = \frac{3L \sin \theta}{2L_1}$$

$$\longrightarrow d_{\max} = 2d_2$$

$$\frac{\lambda}{\Delta\theta} \approx \frac{2\lambda L_1}{3L \sin \theta}$$

# Length Scales Probed by SANS and NR

## 30-m SANS

$$d_{\max} \approx \frac{\lambda}{\Delta\theta_{\min}} \approx 300 \text{ nm}$$

(limited by instrument resolution; in effect, source strength)

$$I(0) = \phi V_p (\Delta\rho)^2 d_s T_s$$

$\phi$  = volume fraction

$V_p$  = 'particle' volume

$\Delta\rho$  = scattering contrast

$d_s$  = sample thickness

$T_s$  = sample transmission

for  $V_p = \frac{\pi}{6} d^3$  and 'good' contrast  
particle diameter

$$\phi d^3 \geq 5 \times 10^{-4} \text{ nm}^3$$

$d_{\min}$	$\phi$
1 nm	0.05 %

for NCNR 30 m SANS instruments

## NR

$$d_{\max} \approx \frac{\lambda}{\Delta\theta_{\min}} \approx 500 \text{ nm}$$

$$R_{\min} \approx 10^{-8} \approx \frac{(8\pi \Delta\rho)^2}{Q_{\max}^4}$$

for NCNR instruments

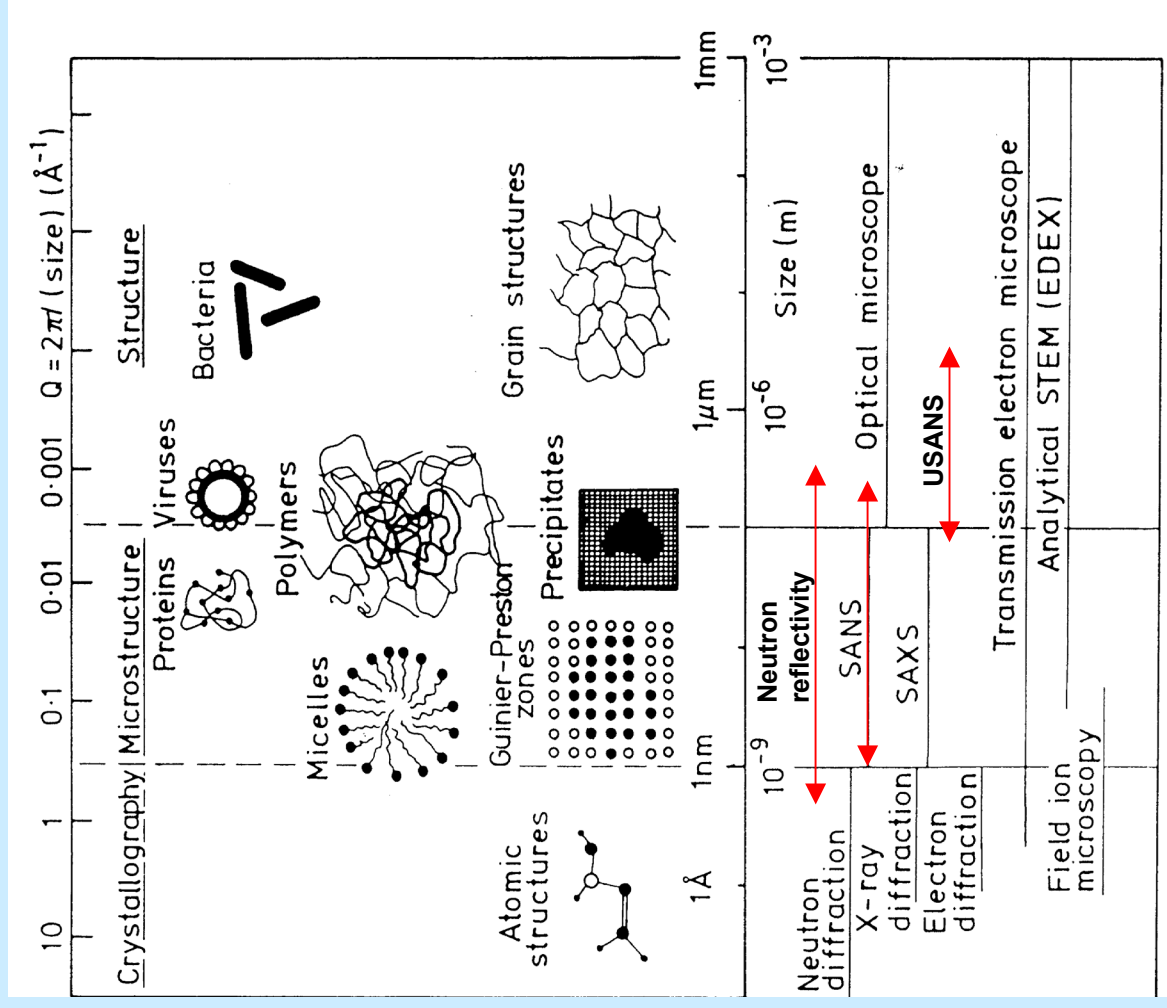
for  $\Delta\rho \approx 3 \times 10^{-6} \text{ \AA}^{-2}$  (good contrast)

$$Q_{\max} \sim 0.8 \text{ \AA}^{-1}$$

$$d_{\min} \approx \frac{2\pi}{Q_{\max}} \approx 0.8 \text{ nm}$$



# Techniques for the Measurement of Microstructure



## Why Neutrons for SAS and Reflectometry?

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- Unique Control of Scattering Contrast by Deuterium Labeling and H- and D-Solvent Mixtures
- Uniquely Powerful Probe of Magnetic Structure

Also,

- highly penetrating even at long wavelengths
- equally sensitive to light and heavy elements
- nondestructive

# SANS APPLICATIONS

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## POLYMERS:

- Conformation of Polymer Molecules in Solution and in the bulk
- Structure of Microphase-Separated Block Copolymers
- Factors Affecting Miscibility of Polymer Blends

## BIOLOGY:

- Organization of Biomolecular Complexes in Solution
- Conformation Changes Affecting Function of Proteins, Enzymes, DNA/Protein complexes, Membranes, etc.
- Mechanisms and Pathways for Protein Folding and DNA Supercoiling

## CHEMISTRY:

- Structure and Interactions in Colloidal Suspensions, Microemulsions, Surfactant Micelles, etc.
- Microporosity of Chemical Absorbents
- Mechanisms of Molecular Self-Assembly in Solutions and on Surfaces of Microporous Media

# *In Situ* SANS Study of Evolution of Porosity in Low-K Films

R.M. Briber and G.Y. Yang

University of Maryland

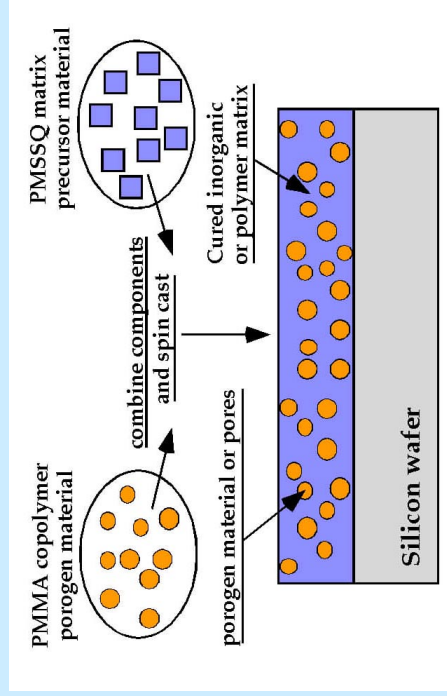
E. Huang, H.-C. Kim,

W. Volksen and R.D. Miller

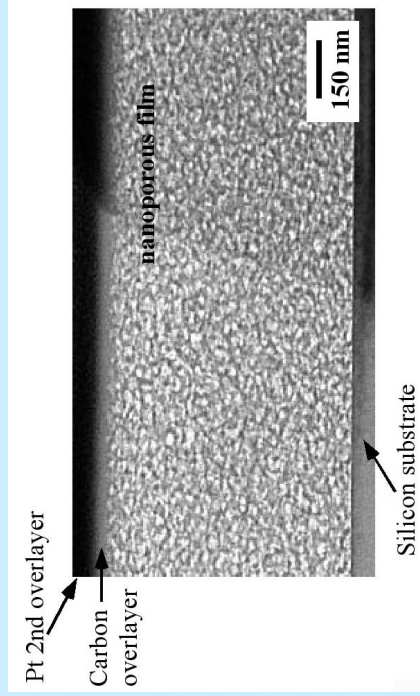
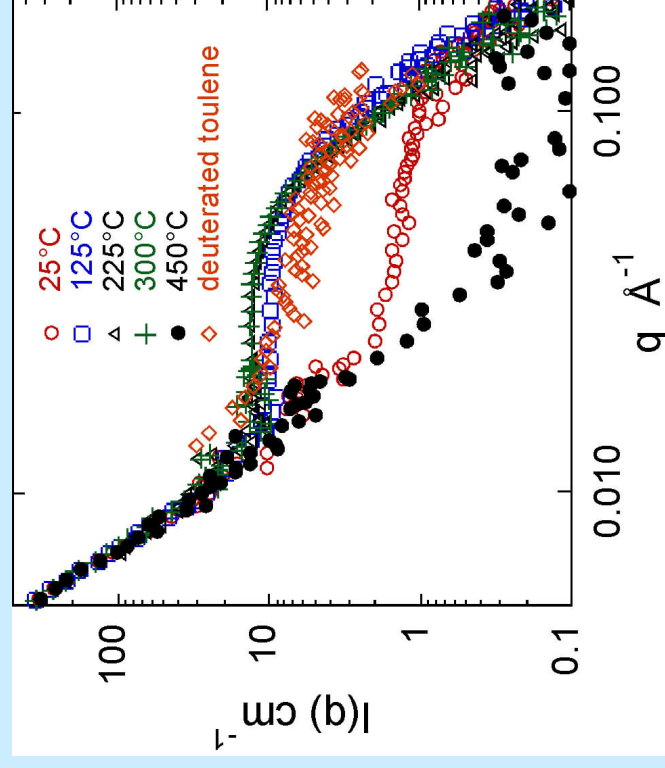
IBM Almaden Res. Center

K. Shin

SUNY Stonybrook



- Use deuterated poragen to introduce contrast in as-spun films
- Follow evolution of poragen
- Backfill poragen-free final material with deuterated wetting fluid to compare pore with poragen structure



# SANS APPLICATIONS

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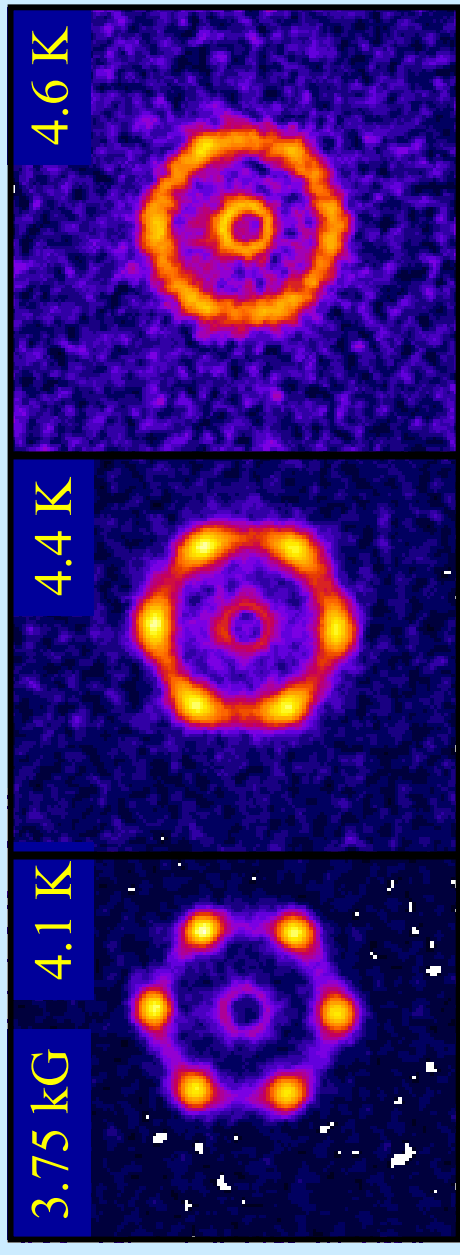
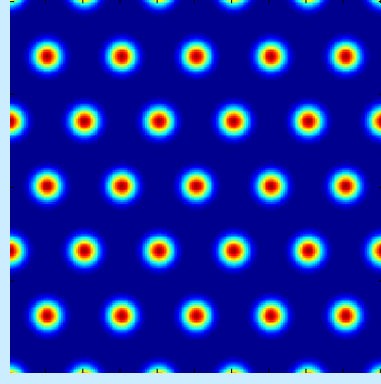
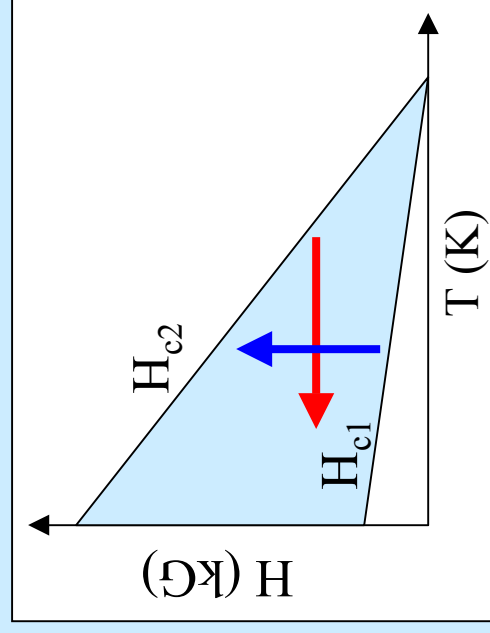
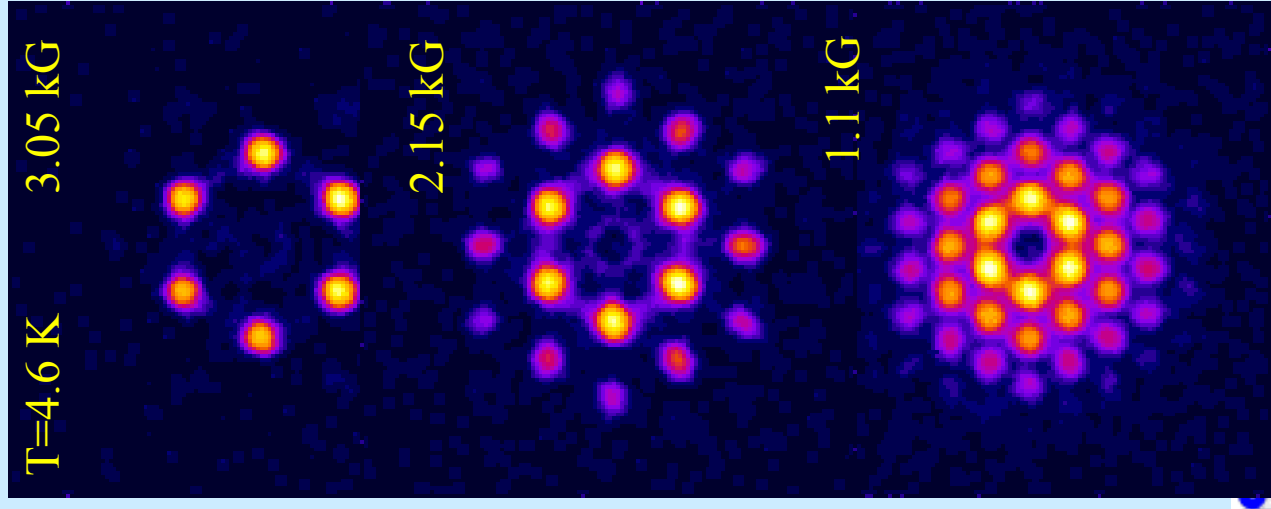
## METALS AND CERAMICS:

- Kinetics and Morphology of Precipitate Growth in Alloys and Glasses
- Defect Structures (e.g. microcracks, voids) Resulting from Creep, Fatigue or Radiation Damage
- Grain and Defect Structures in Nanocrystalline Metals and Ceramics

## MAGNETISM:

- Magnetic Ordering and Phase Transitions in Ferromagnets, Spin Glasses, Magnetic Superconductors, etc.
- Flux-Line Lattices in Superconductors

# Vortex Matter in Superconductor Nb

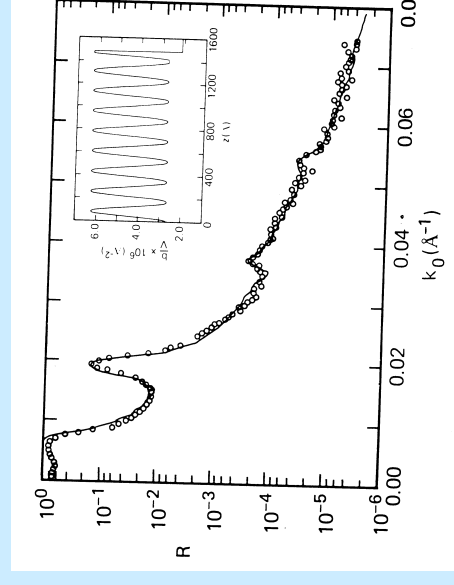
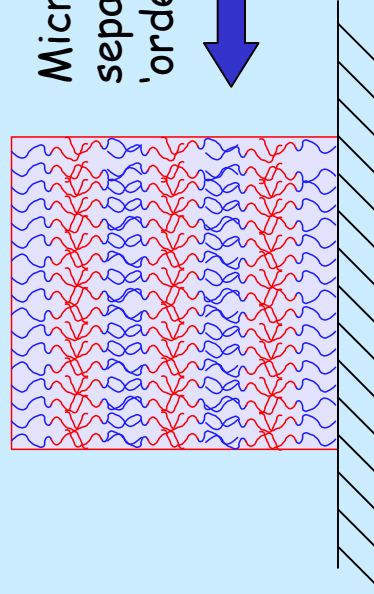
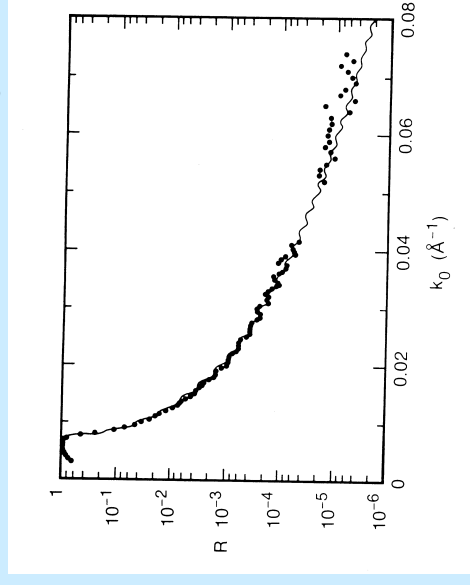
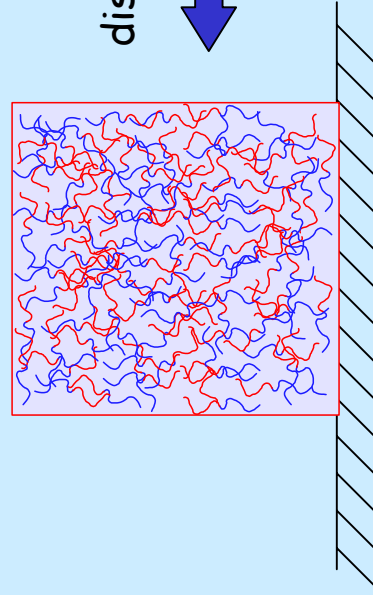


X. S. Ling and S.-R. Park (Brown University)  
S.-M Choi, D. Dender and J. Lynn, (NCNR/NIST)

# Neutron Reflectivity Application Areas

## Polymers:

- polymer phase behavior in thin films
- e.g. order-disorder phase transitions of block copolymers



# Neutron Reflectivity Application Areas

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## Polymers:

- Polymer Interdiffusion at Interfaces
- Factors Affecting Wetting and Dewetting
- Polymer conformation and concentration profiles at solid-liquid and liquid-air interfaces

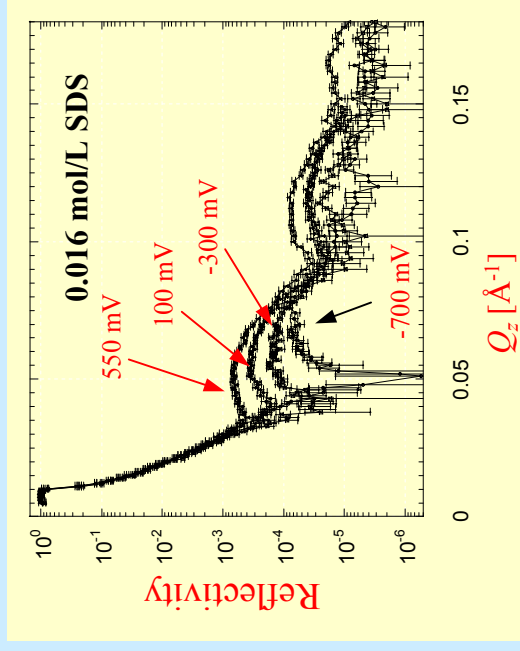
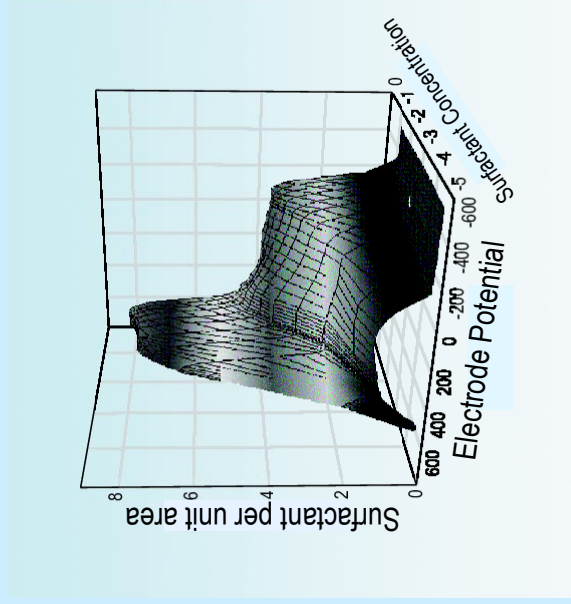
## Chemistry:

- Langmuir-Blodgett films
- Self-Assembled monolayers, bilayers, etc.
- Electrochemical reactions

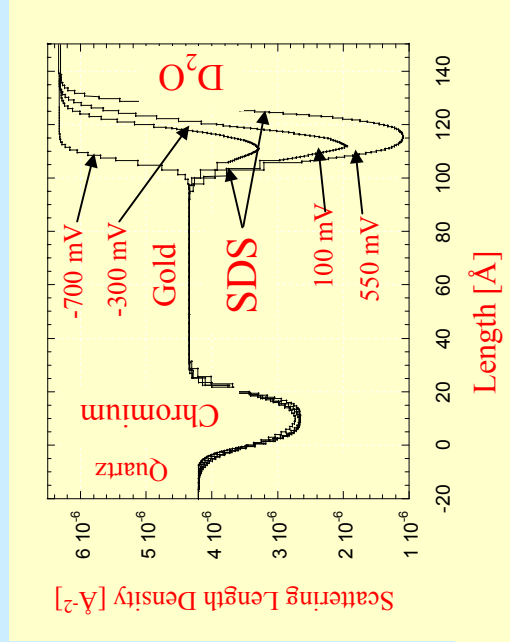
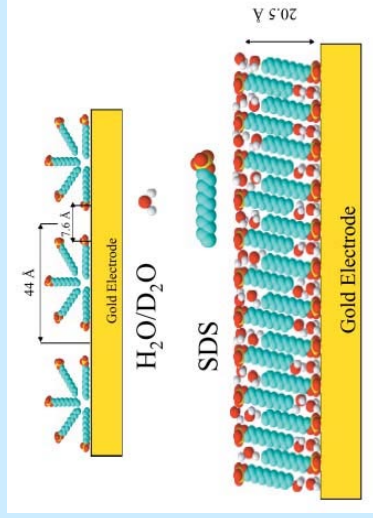


# NR Study of Surfactants at Electrode Surfaces

I. Burgess, et al. (U. Guelph), J. Majewski & G. Smith (LANL), S. Satiya & R. Ivkov (NCNR)



Neutron reflectivity combined with electrochemical studies and AFM yield picture below of adsorbed surfactant film structure



Electrical potential controls adsorption and desorption of surfactant

# Neutron Reflectivity Application Areas

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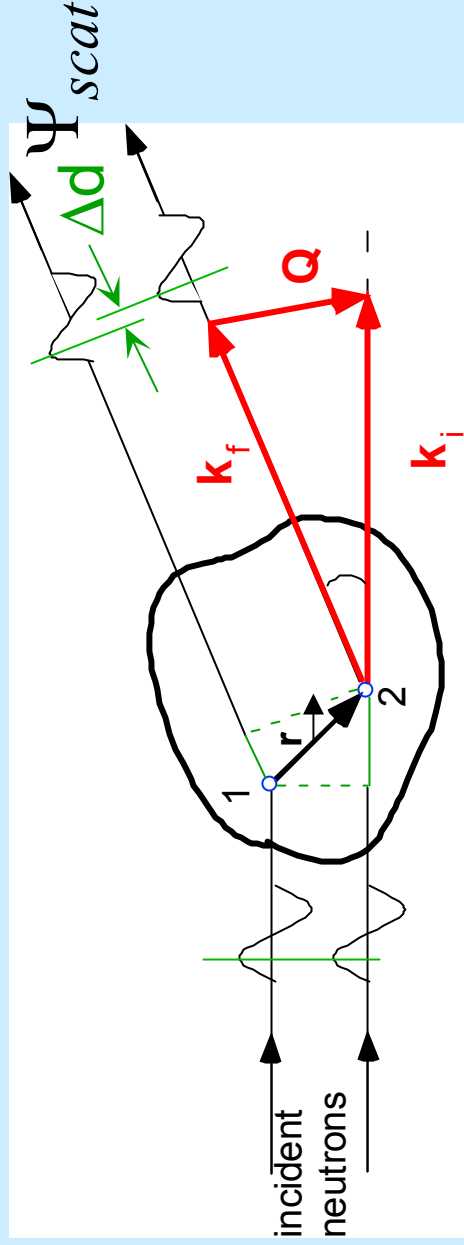
## Biology:

- Location of Peptides in Biomimetic Single Bilayer Membranes
- Protein Adsorption/Desorption on Self-Assembled Monolayers
- Vectorially-Oriented Protein Monolayers

## Magnetism:

- Magnetic Structure and Interlayer Coupling in GMR Multilayer Thin Films
- Magnetic Coupling and Ordering across Non-Magnetic Layers
- Spin Structures Associated with Exchange-Biased Magnetic Thin Films

# Appendix A. Scattering from Two Nuclei



$$\Delta\phi = 2\pi \frac{\Delta d}{\lambda}$$

$$\Delta\phi = \vec{r} \cdot \vec{k}_i - \vec{r} \cdot \vec{k}_f$$

$$\Delta\phi = \vec{r} \cdot (\vec{k}_i - \vec{k}_f)$$

$$\Delta\phi = \vec{r} \cdot \vec{Q}$$

$$\Psi_{scat} = -\frac{b_1}{R} e^{ikR} - \frac{b_2}{R} e^{i(kR + \Delta\phi)}$$

Scattered wave function

for N nuclei

SAS of X rays - Guinier (1955), Ch.1  
 Polymers and Neutron Scattering,  
 Huggins & Benoît (1994), p.11

$$\frac{d\sigma}{d\Omega} = \frac{1}{N} \left| \sum_{i=1}^N b_i e^{i\vec{Q} \cdot \vec{r}_i} \right|^2$$

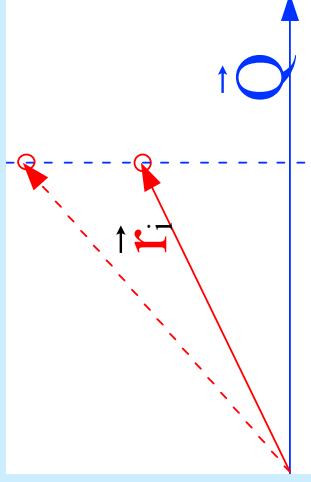
## Appendix A. Scattering from N Nuclei

$$\frac{d\sigma}{d\Omega} = \frac{1}{N} \left| \sum_1^N b_i e^{i\vec{Q}\cdot\vec{r}_i} \right|^2$$

Scattering cross section: # neutrons scattering in direction corresponding to  $\vec{Q}$ , divided by # incident per unit area

$$\vec{r}_i = \vec{r}_{//} + \vec{r}_{\perp}$$

$$\vec{Q} \cdot \vec{r}_i = Q r_{//}$$



Only components of  $r_i$  parallel to  $\vec{Q}$  contribute to summation

Therefore, diffraction probes structure in the direction of  $\vec{Q}$  *only*!!